

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	54825	(stag\$3 or tabl\$3 or platform\$4)same(rotat\$6 or mov\$6 or orientation\$4 or fly\$4 or motion\$4)same(camera\$4 or reader\$4 or scanner\$4 or sensor\$3 or microscap\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 14:21
L2	55518	(stag\$3 or tabl\$3 or platform\$4)same(rotary\$4 or rotat\$6 or mov\$6 or orientation\$4 or fly\$4 or motion\$4)same(camera\$4 or reader\$4 or scanner\$4 or sensor\$3 or microscap\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 09:28
L3	13379	2 same(correct\$4 or adjust\$6 or compensat\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 14:22
L4	4667	3 same(captur\$3 or detect\$4 or extrat\$6)	US-PGPUB; USPAT	OR	ON	2007/07/24 14:23
L5	4984	3 same(captur\$3 or detect\$4 or extrat\$6 or inspect\$6)	US-PGPUB; USPAT	OR	ON	2007/07/24 09:34
L6	1075	5 same((rotat\$6 or mov\$6 or orientation\$4 or fly\$4 or motion\$4)near10 control\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 14:23
L7	331	6 same(measur\$5 or calculat\$4 or comput\$4)near10(position\$3 or displac\$6 or orientation\$4 or shift\$4 or mov\$4 or motion\$4 or angl\$6)	US-PGPUB; USPAT	OR	ON	2007/07/24 14:23
L8	18	7 same(video\$3)	US-PGPUB; USPAT	OR	ON	2007/07/24 09:56
L9	1	"6496247".PN.	USPAT; USOCR	OR	ON	2007/07/24 09:43
L10	1	"6011612".PN.	USPAT; USOCR	OR	ON	2007/07/24 09:43
L11	1	"5831716".PN.	USPAT; USOCR	OR	ON	2007/07/24 09:43
L12	1	"5663784".PN.	USPAT; USOCR	OR	ON	2007/07/24 09:43
L13	1	"5834160".PN.	USPAT; USOCR	OR	ON	2007/07/24 09:44
L14	1	"5812308".PN.	USPAT; USOCR	OR	ON	2007/07/24 09:45
L15	1	"5627854".PN.	USPAT; USOCR	OR	ON	2007/07/24 09:45
L16	1	"5627854".PN.	USPAT; USOCR	OR	ON	2007/07/24 09:45

EAST Search History

L17	1	"4914658".PN.	USPAT; USOCR	OR	ON	2007/07/24 09:45
L18	5	(theta-theta near10 coordinat\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 13:37
L19	3	(theta-theta near10 stag\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 09:58
L20	2	(theta-theta near10 imag\$3)	US-PGPUB; USPAT	OR	ON	2007/07/24 13:38
L21	0	(theta-theta near10 camera\$2)	US-PGPUB; USPAT	OR	ON	2007/07/24 13:38
L22	1314	(theta near10 camera\$2)	US-PGPUB; USPAT	OR	ON	2007/07/24 13:38
L23	327	22 same rotat\$6	US-PGPUB; USPAT	OR	ON	2007/07/24 13:39
L24	178	23 same imag\$4	US-PGPUB; USPAT	OR	ON	2007/07/24 13:39
L25	90	24 same(mov\$6 or orientation\$4 or fly\$4 or motion\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 13:41
L26	0	25 same(microcop\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 14:20
L27	0	25 same(microscop\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 13:42
L28	0	24 same(microscop\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 13:42
L29	1	25 same(micro\$6)	US-PGPUB; USPAT	OR	ON	2007/07/24 14:21
L30	2174	(stag\$3 or tabl\$3 or platform\$4)same(rotat\$6 or mov\$6 or orientation\$4 or fly\$4 or motion\$4)same(camera\$4 or reader\$4 or scanner\$4 or sensor\$3 or microscap\$4)same(microscop\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 14:21
L31	567	30 same(correct\$4 or adjust\$6 or compensat\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 14:22
L32	221	31 same(captur\$3 or detect\$4 or extrat\$6)	US-PGPUB; USPAT	OR	ON	2007/07/24 14:23
L33	67	32 same((rotat\$6 or mov\$6 or orientation\$4 or fly\$4 or motion\$4)near10 control\$4)	US-PGPUB; USPAT	OR	ON	2007/07/24 14:23
L34	34	33 same(measur\$5 or calculat\$4 or comput\$4)near10(position\$3 or displac\$6 or orientation\$4 or shift\$4 or mov\$4 or motion\$4 or angl\$6)	US-PGPUB; USPAT	OR	ON	2007/07/24 14:23
L35	1	"6454437".PN.	USPAT; USOCR	OR	ON	2007/07/24 14:35

EAST Search History

L36	1	"6424733".PN.	USPAT; USOCR	OR	ON	2007/07/24 14:35
L37	1	"6098887".PN.	USPAT; USOCR	OR	ON	2007/07/24 14:36



[Search Result - Print Format](#)

[< Back](#)

Key: IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, II CNF = IEE Conference, IEEE STD = IEEE Standard

1. **Capture rate enhancement method of 0.1 μm -level defects by pattern matching inspectors**
Sakurai, K.; Onoyama, A.; Ishii, H.; Oka, K.; Yamanishi, K.;
Semiconductor Manufacturing Conference Proceedings, 1999 IEEE International Symposium on
11-13 Oct. 1999 Page(s):131 - 134
IEEE CNF
2. **Nanostructure fabrication with laser radiation in the nearfield of a scanning-probe microscope tip**
Jersch, J.; Dickmann, K.;
Lasers and Electro-Optics, 1996. CLEO '96., Summaries of papers presented at the Conference on
2-7 June 1996 Page(s):461
IEEE CNF
3. **A novel method to correct the nonlinearity of piezoelectric scanner in STM by DNA evolution algorithm**
Ziyuan Huang; Minrui Fei;
TENCON '02. Proceedings. 2002 IEEE Region 10 Conference on Computers, Communications, Control and Power
Engineering
Volume 3, 28-31 Oct. 2002 Page(s):1471 - 1474 vol.3
IEEE CNF
4. **Detection sensitivity enhancements for fluorescence imaging with multi-photon excitation microscopy**
Wokosin, D.L.; Amos, W.B.; White, J.G.;
Engineering in Medicine and Biology Society, 1998. Proceedings of the 20th Annual International Conference of the
IEEE
Volume 4, 29 Oct.-1 Nov. 1998 Page(s):1707 - 1714 vol.4
IEEE CNF
5. **Characterization of LANDSAT-4 MSS And TM Digital Image Data**
Malila, William A.; Metzler, Michael D.; Rice, Daniel P.; Crist, Eric P.;
Geoscience and Remote Sensing, IEEE Transactions on
Volume GE-22, Issue 3, May 1984 Page(s):177 - 191
IEEE JNL
6. **An Image Model and Segmentation Algorithm for Reflectance Confocal Images of In Vivo Cervical Tissue**
Luck, B.L.; Carlson, K.D.; Bovik, A.C.; Richards-Kortum, R.R.;
Image Processing, IEEE Transactions on
Volume 14, Issue 9, Sept. 2005 Page(s):1265 - 1276
IEEE JNL
7. **Nano/micromechanical tools for nanoscience and nanoengineering**
Ono, T.; Miyashita, H.; Iwami, K.; Sang-Jin Kim; Yu-Ching Lin; Esashi, M.;
Micro-Nanomechatronics and Human Science, 2004 and The Fourth Symposium Micro-Nanomechatronics for
Information-Based Society, 2004. Proceedings of the 2004 International Symposium on
31 Oct.-3 Nov. 2004 Page(s):39 - 46
IEEE CNF
8. **The numerical analyses of microscopic organisms**
Ballan, M.;
Signal Processing and Communications Applications Conference, 2004. Proceedings of the IEEE 12th

28-30 April 2004 Page(s):230 - 233

IEEE CNF

9. **Laser nano-engineering with the assistance of scanning probe microscope and optical resonance in microparticles**
 Lu, Y.F.; Hu, B.; Mai, Z.H.; Huang, S.M.; Zhang, L.; Zheng, Y.W.; Luk'yanchuk, B.S.; Song, W.D.; Hong, M.H.; Choi T.C.;
 Lasers and Electro-Optics, 2001. CLEO/Pacific Rim 2001. The 4th Pacific Rim Conference on
 Volume 1, 15-19 July 2001 Page(s):I-30 - I-31 vol.1
 IEEE CNF
10. **Enhanced resolution of reflection-mode near-field scanning optical microscope by detecting 2nd harmonic signals**
 June-Hyoung Park; Kim, M.R.; Wonho Jhe;
 Lasers and Electro-Optics, 1999. CLEO/Pacific Rim '99. The Pacific Rim Conference on
 Volume 4, 30 Aug.-3 Sept. 1999 Page(s):1181 - 1182 vol.4
 IEEE CNF
11. **Simple Linear Models of Scanning Impedance Imaging for Fast Reconstruction of Relative Conductivity of Biological Samples**
 Oliphant, T.E.; Liu, H.; Hawkins, A.R.; Schultz, S.M.;
 Biomedical Engineering, IEEE Transactions on
 Volume 53, Issue 11, Nov. 2006 Page(s):2323 - 2332
 IEEE JNL
12. **Computer enhancement of scanning electron micrographs**
 Lewis, B.; Sakrison, D.;
 Circuits and Systems, IEEE Transactions on
 Volume 22, Issue 3, Mar 1975 Page(s):267 - 278
 IEEE JNL
13. **Digital processing of VLSI circuit images obtained from a scanning electron microscope**
 Zolghadrasli, A.;
 Circuits and Systems, IEEE Transactions on
 Volume 37, Issue 6, June 1990 Page(s):824 - 827
 IEEE JNL
14. **Image enhancement in the scanning acoustic microscope using analogue filters**
 Wickramasinghe, H.K.; Heiserman, J.;
 Electronics Letters
 Volume 13, Issue 25, December 8 1977 Page(s):776 - 777
 IEE JNL
15. **Three-dimensional enhancement of confocal scanning laser fluorescence microscope images for vascular reconstruction**
 Ip, H.H.S.; Feng, J.J.; Cheng, S.H.;
 Pattern Recognition, 2002. Proceedings. 16th International Conference on
 Volume 3, 11-15 Aug. 2002 Page(s):863 - 866 vol.3
 IEEE CNF
16. **Cell contour detection in corneal endothelium in-vivo microscopy**
 Foracchia, M.; Ruggeri, A.;
 Engineering in Medicine and Biology Society, 2000. Proceedings of the 22nd Annual International Conference of the
 IEEE
 Volume 2, 23-28 July 2000 Page(s):1033 - 1035 vol.2
 IEEE CNF
17. **Giant near-field optical enhancement with subnanometer tip-sample distance sensitivity**

Martinez, O.E.; Bragas, A.V.; Lester, M.;
Quantum Electronics and Laser Science Conference, 2000. (QELS 2000). Technical Digest
7-12 May 2000 Page(s):61 - 62
IEEE CNF

18. Investigation of the reflow behavior of GeO₂-SiO₂ glasses deposited by plasma enhanced chemical vapor deposition

Simpson, D.L.; Croswell, R.T.; Reisman, A.; Williams, C.K.; Temple, D.;
Plasma Science, 1998. 25th Anniversary. IEEE Conference Record - Abstracts. 1998 IEEE International on
1-4 June 1998 Page(s):144
IEEE CNF

19. Image restoration and wave-field error removal in holographic acoustic microscopy

Chiao, R.Y.; Lee, H.; Wade, G.;
Acoustics, Speech, and Signal Processing, 1989. ICASSP-89., 1989 International Conference on
23-26 May 1989 Page(s):1508 - 1511 vol.3
IEEE CNF

20. Digital implementation of a laser scanning confocal microscope using image enhancement algorithms

Kesterson, J.; Koenig, D.;
Acoustics, Speech, and Signal Processing, 1992. ICASSP-92., 1992 IEEE International Conference on
Volume 3, 23-26 March 1992 Page(s):89 - 92 vol.3
IEEE CNF

21. Data handling in confocal microscopy

Browne, M.A.;
New Microscopies in Medicine and Biology, IEE Colloquium on
1994 Page(s):1
IEEE CNF

22. A Radically New Principle of Operation Seismic Detector of Nano-Scale Vibrations

Gevorgyan, S. G.; Gevorgyan, V. S.; Shirinyan, H. G.; Karapetyan, G. H.; Sarkisyan, A. G.;
Applied Superconductivity, IEEE Transactions on
Volume 17, Issue 2, June 2007 Page(s):629 - 632
IEEE JNL

23. Superresolution Digital Image Enhancement by Subpixel Image Translation With a Scanning Micromirror

Yu, K.; Park, N.; Lee, D.; Solgaard, O.;
Selected Topics in Quantum Electronics, IEEE Journal of
Volume 13, Issue 2, March-april 2007 Page(s):304 - 311
IEEE JNL

24. The Preparation of Nanocrystalline Silicon by Plasma-Enhanced Hydrogenation for the Fabrication of Light Emitting Diodes

Jamei, M.; Karbassian, F.; Mohajerzadeh, S.; Abdi, Y.; Robertson, M. D.; Yuill, S.;
Electron Device Letters, IEEE
Volume 28, Issue 3, March 2007 Page(s):207 - 210
IEEE JNL

25. Photon-counting chip for avalanche detectors

F. Zappa; A. Lotito; S. Tisa;
Photonics Technology Letters, IEEE
Volume 17, Issue 1, Jan. 2005 Page(s):184 - 186
IEEE JNL